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Understanding [Embedded - Microprocessors](#)

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of [Embedded - Microprocessors](#)

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	PowerPC G4
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	1.42GHz
Co-Processors/DSP	Multimedia; SIMD
RAM Controllers	-
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	-
SATA	-
USB	-
Voltage - I/O	1.5V, 1.8V, 2.5V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	360-CBGA, FCCBGA
Supplier Device Package	360-FCCBGA (25x25)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mc7448vu1420lc

Figure 2 shows the overshoot and undershoot voltage on the MPC7448.

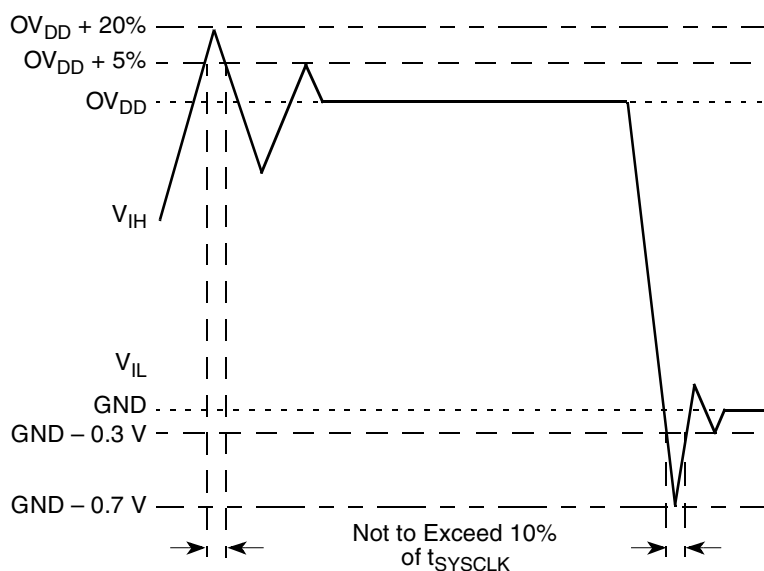


Figure 2. Overshoot/Undershoot Voltage

The MPC7448 provides several I/O voltages to support both compatibility with existing systems and migration to future systems. The MPC7448 core voltage must always be provided at the nominal voltage (see Table 4). The input voltage threshold for each bus is selected by sampling the state of the voltage select pins at the negation of the signal $\overline{\text{HRESET}}$. The output voltage will swing from GND to the maximum voltage applied to the OV_{DD} power pins. Table 3 provides the input threshold voltage settings. Because these settings may change in future products, it is recommended that BVSEL[0:1] be configured using resistor options, jumpers, or some other flexible means, with the capability to reconfigure the termination of this signal in the future, if necessary.

Table 3. Input Threshold Voltage Setting

BVSEL0	BVSEL1	I/O Voltage Mode ¹	Notes
0	0	1.8 V	2, 3
0	1	2.5 V	2, 4
1	0	1.5 V	2
1	1	2.5 V	4

Notes:

- Caution:** The I/O voltage mode selected must agree with the OV_{DD} voltages supplied. See Table 4.
- If used, pull-down resistors should be less than 250 Ω .
- The pin configuration used to select 1.8V mode on the MPC7448 is not compatible with the pin configuration used to select 1.8V mode on the MPC7447A and earlier devices.
- The pin configuration used to select 2.5V mode on the MPC7448 is fully compatible with the pin configuration used to select 2.5V mode on the MPC7447A and earlier devices.

when running a typical benchmark at temperatures in a typical system. The Full-Power Mode–Thermal value is intended to represent the sustained power consumption of the device when running a typical code sequence at high temperature and is recommended to be used as the basis for designing a thermal solution; see [Section 9.7, “Power and Thermal Management Information”](#) for more information on thermal solutions. The Full-Power Mode–Maximum value is recommended to be used for power supply design because this represents the maximum peak power draw of the device that a power supply must be capable of sourcing without voltage droop. For information on power consumption when dynamic frequency switching is enabled, see [Section 9.7.5, “Dynamic Frequency Switching \(DFS\)”](#).

Table 7. Power Consumption for MPC7448 at Maximum Rated Frequency

	Die Junction Temperature (T _j)	Maximum Processor Core Frequency (Speed Grade, MHz)				Unit	Notes
		1000 MHz	1420 MHz	1600 MHz	1700 MHz		
Full-Power Mode							
Typical	65 •C	15.0	19.0	20.0	21.0	W	1, 2
Thermal	105 •C	18.6	23.3	24.4	25.6	W	1, 5
Maximum	105 •C	21.6	27.1	28.4	29.8	W	1, 3
Nap Mode							
Typical	105 •C	11.1	11.8	13.0	13.0	W	1, 6
Sleep Mode							
Typical	105 •C	10.8	11.4	12.5	12.5	W	1, 6
Deep Sleep Mode (PLL Disabled)							
Typical	105 •C	10.4	11.0	12.0	12.0	W	1, 6

Notes:

1. These values specify the power consumption for the core power supply (V_{DD}) at nominal voltage and apply to all valid processor bus frequencies and configurations. The values do not include I/O supply power (OV_{DD}) or PLL supply power (AV_{DD}). OV_{DD} power is system dependent but is typically < 5% of V_{DD} power. Worst case power consumption for AV_{DD} < 13 mW. Freescale also offers MPC7448 part numbers that meet lower power consumption specifications; for more information on these devices, see [Section 11.2, “Part Numbers Not Fully Addressed by This Document.”](#)
2. Typical power consumption is an average value measured with the processor operating at its rated maximum processor core frequency (except for Deep Sleep Mode), at nominal recommended V_{DD} (see [Table 4](#)) and 65°C while running the Dhrystone 2.1 benchmark and achieving 2.3 Dhrystone MIPS/MHz. This parameter is not 100% tested but periodically sampled.
3. Maximum power consumption is the average measured with the processor operating at its rated maximum processor core frequency, at nominal V_{DD} and maximum operating junction temperature (see [Table 4](#)) while running an entirely cache-resident, contrived sequence of instructions to keep all the execution units maximally busy.
4. Doze mode is not a user-definable state; it is an intermediate state between full-power and either nap or sleep mode. As a result, power consumption for this mode is not tested.
5. Thermal power consumption is an average value measured at the nominal recommended V_{DD} (see [Table 4](#)) and 105 °C while running the Dhrystone 2.1 benchmark and achieving 2.3 Dhrystone MIPS/MHz. This parameter is not 100% tested but periodically sampled.
6. Typical power consumption for these modes is measured at the nominal recommended V_{DD} (see [Table 4](#)) and 105 °C in the mode described. This parameter is not 100% tested but is periodically sampled.

Table 8. Clock AC Timing Specifications

At recommended operating conditions. See [Table 4](#).

Characteristic		Symbol	Maximum Processor Core Frequency (Speed Grade)								Unit	Notes
			1000 MHz		1420 MHz		1600 MHz		1700 MHz			
			Min	Max	Min	Max	Min	Max	Min	Max		
Processor core frequency	DFS mode disabled	f _{core}	600	1000	600	1420	600	1600	600	1700	MHz	1, 8
	DFS mode enabled	f _{core—DF}	300	500	300	710	300	800	300	850		9
VCO frequency		f _{VCO}	600	1000	600	1420	600	800	600	1700	MHz	1, 10
SYSCLK frequency		f _{SYSCLK}	33	200	33	200	33	200	33	200	MHz	1, 2, 8
SYSCLK cycle time		t _{SYSCLK}	5.0	30	5.0	30	5.0	30	5.0	30	ns	2
SYSCLK rise and fall time		t _{KR} , t _{KF}	—	0.5	—	0.5	—	0.5	—	0.5	ns	3
SYSCLK duty cycle measured at OV _{DD} /2		t _{KHKL} / t _{SYSCLK}	40	60	40	60	40	60	40	60	%	4
SYSCLK cycle-to-cycle jitter			—	150	—	150	—	150	—	150	ps	5, 6
Internal PLL relock time			—	100	—	100	—	100	—	100	μs	7

Notes:

- Caution:** The SYSCLK frequency and PLL_CFG[0:5] settings must be chosen such that the resulting SYSCLK (bus) frequency, processor core frequency, and PLL (VCO) frequency do not exceed their respective maximum or minimum operating frequencies. Refer to the PLL_CFG[0:5] signal description in [Section 9.1.1, "PLL Configuration,"](#) for valid PLL_CFG[0:5] settings.
- Actual maximum system bus frequency is system-dependent. See [Section 5.2.1, "Clock AC Specifications."](#)
- Rise and fall times for the SYSCLK input measured from 0.4 to 1.4 V
- Timing is guaranteed by design and characterization.
- Guaranteed by design
- The SYSCLK driver's closed loop jitter bandwidth should be less than 1.5 MHz at –3 dB.
- Relock timing is guaranteed by design and characterization. PLL-relock time is the maximum amount of time required for PLL lock after a stable V_{DD} and SYSCLK are reached during the power-on reset sequence. This specification also applies when the PLL has been disabled and subsequently re-enabled during sleep mode. Also note that \overline{HRESET} must be held asserted for a minimum of 255 bus clocks after the PLL-relock time during the power-on reset sequence.
- This reflects the maximum and minimum core frequencies when the dynamic frequency switching feature (DFS) is disabled. f_{core_DFS} provides the maximum and minimum core frequencies when operating in a DFS mode.
- This specification supports the Dynamic Frequency Switching (DFS) feature and is applicable only when one of the DFS modes (divide-by-2 or divide-by-4) is enabled. When DFS is disabled, the core frequency must conform to the maximum and minimum frequencies stated for f_{core} .
- Use of the DFS feature does not affect VCO frequency.

Figure 3 provides the SYSCLK input timing diagram.

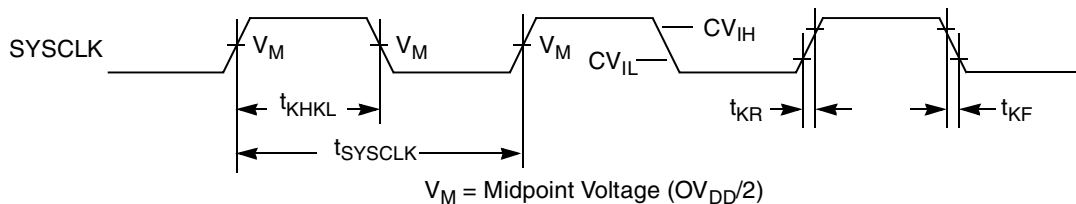


Figure 3. SYSCLK Input Timing Diagram

5.2.2 Processor Bus AC Specifications

Table 9 provides the processor bus AC timing specifications for the MPC7448 as defined in Figure 4 and Figure 5.

Table 9. Processor Bus AC Timing Specifications¹

At recommended operating conditions. See Table 4.

Parameter	Symbol ²	All Speed Grades		Unit	Notes
		Min	Max		
Input setup times: A[0:35], AP[0:4] D[0:63], DP[0:7] AACK, ARTRY, BG, CKSTP_IN, DBG, DTI[0:3], GBL, TT[0:4], QACK, TA, TBEN, TEA, TS, EXT_QUAL, PMON_IN, SHD[0:1] BMODE[0:1], BVSEL[0:1]	t _{AVKH} t _{DVKH} t _{IVKH} t _{MVKH}	1.5 1.5 1.5 1.5	— — — —	ns	— — — 8
Input hold times: A[0:35], AP[0:4] D[0:63], DP[0:7] AACK, ARTRY, BG, CKSTP_IN, DBG, DTI[0:3], GBL, TT[0:4], QACK, TA, TBEN, TEA, TS, EXT_QUAL, PMON_IN, SHD[0:1] BMODE[0:1], BVSEL[0:1]	t _{AXKH} t _{DXKH} t _{IXKH} t _{MXKH}	0 0 0 0	— — — —	ns	— — — 8
Output valid times: A[0:35], AP[0:4] D[0:63], DP[0:7] BR, CI, DRDY, GBL, HIT, PMON_OUT, QREQ, TBST, TSIZ[0:2], TT[0:4], WT TS ARTRY, SHD[0:1]	t _{KHAV} t _{KHDV} t _{KHOV} t _{KHTSV} t _{KHARV}	— — — — —	1.8 1.8 1.8 1.8 1.8	ns	
Output hold times: A[0:35], AP[0:4] D[0:63], DP[0:7] BR, CI, DRDY, GBL, HIT, PMON_OUT, QREQ, TBST, TSIZ[0:2], TT[0:4], WT TS ARTRY, SHD[0:1]	t _{KHAX} t _{KHDX} t _{KHOX} t _{KHTSX} t _{KHARX}	0.5 0.5 0.5 0.5 0.5	— — — — —	ns	
SYSCLK to output enable	t _{KHOE}	0.5	—	ns	5

Figure 6 provides the input/output timing diagram for the MPC7448.

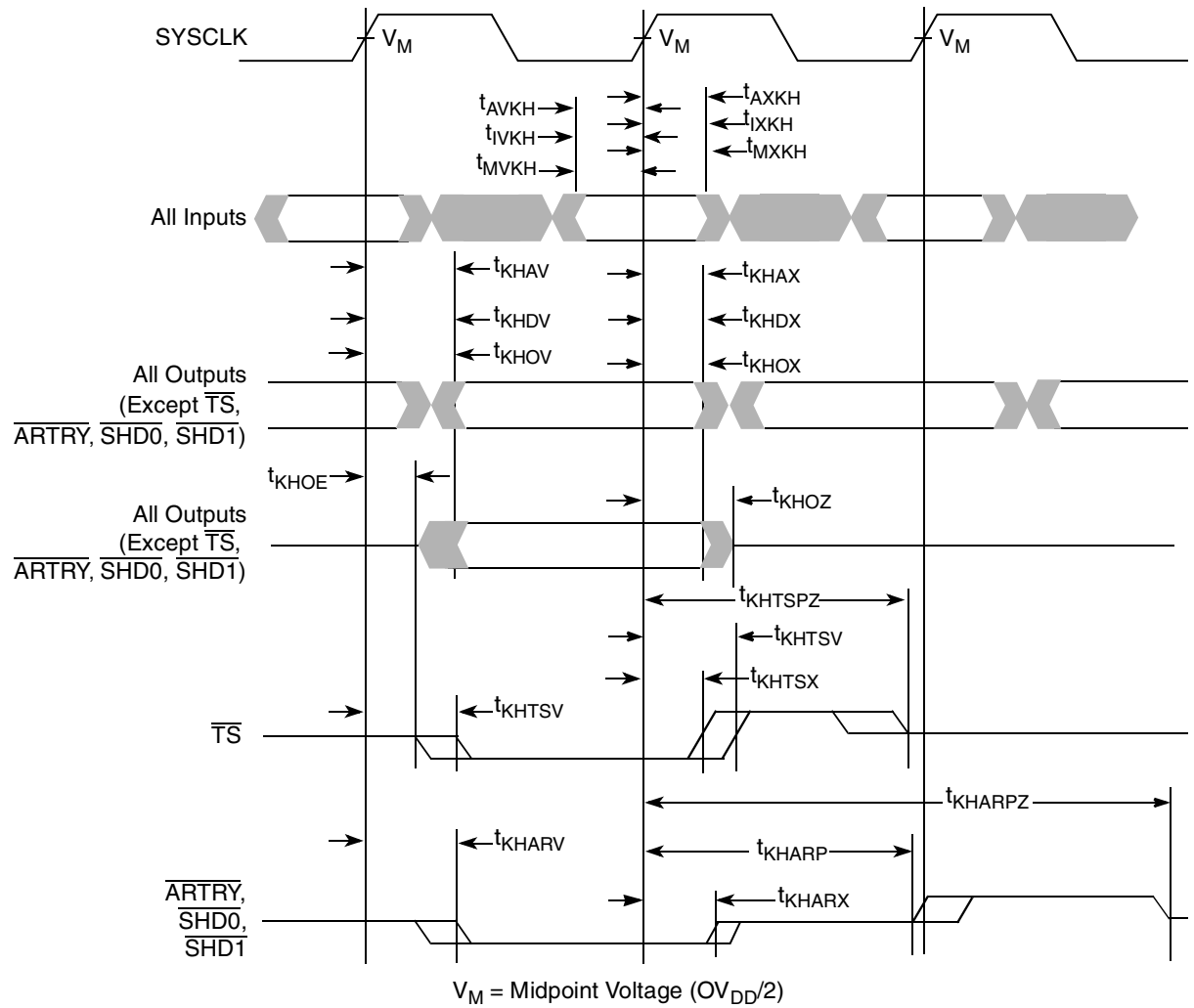


Figure 6. Input/Output Timing Diagram

5.2.3 IEEE Std. 1149.1 AC Timing Specifications

Table 10 provides the IEEE Std. 1149.1 (JTAG) AC timing specifications as defined in Figure 8 through Figure 11.

Table 10. JTAG AC Timing Specifications (Independent of SYSCLK)¹

At recommended operating conditions. See Table 4.

Parameter	Symbol	Min	Max	Unit	Notes
TCK frequency of operation	f_{TCLK}	0	33.3	MHz	
TCK cycle time	t_{TCLK}	30	—	ns	
TCK clock pulse width measured at 1.4 V	t_{HJL}	15	—	ns	
TCK rise and fall times	t_{JR} and t_{JF}	—	2	ns	
\overline{TRST} assert time	t_{TRST}	25	—	ns	2
Input setup times: Boundary-scan data TMS, TDI	t_{DVJH} t_{IVJH}	4 0	— —	ns	3
Input hold times: Boundary-scan data TMS, TDI	t_{DXJH} t_{IXJH}	20 25	— —	ns	3
Valid times: Boundary-scan data TDO	t_{JLDV} t_{JLOV}	4 4	20 25	ns	4
Output hold times: Boundary-scan data TDO	t_{JLDX} t_{JLOX}	30 30	— —	ns	4
TCK to output high impedance: Boundary-scan data TDO	t_{JLDZ} t_{JLOZ}	3 3	19 9	ns	4, 5

Notes:

1. All outputs are measured from the midpoint voltage of the falling/rising edge of TCLK to the midpoint of the signal in question. The output timings are measured at the pins. All output timings assume a purely resistive 50-Ω load (see Figure 7). Time-of-flight delays must be added for trace lengths, vias, and connectors in the system.
2. \overline{TRST} is an asynchronous level sensitive signal. The time is for test purposes only.
3. Non-JTAG signal input timing with respect to TCK.
4. Non-JTAG signal output timing with respect to TCK.
5. Guaranteed by design and characterization.

6 Pin Assignments

Figure 12 (in Part A) shows the pinout of the MPC7448, 360 high coefficient of thermal expansion ceramic ball grid array (HCTE) package as viewed from the top surface. Part B shows the side profile of the HCTE package to indicate the direction of the top surface view.

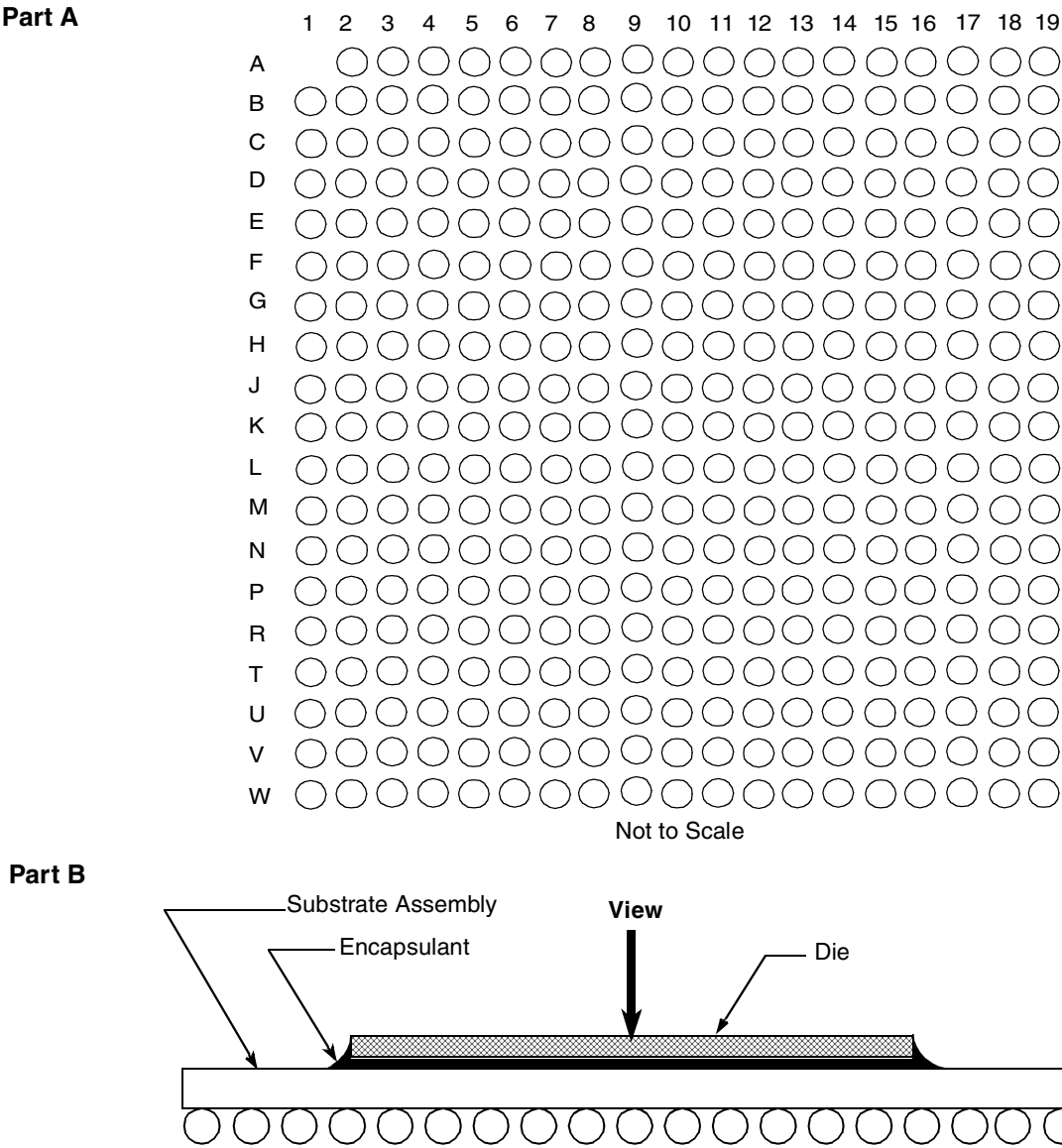


Figure 12. Pinout of the MPC7448, 360 HCTE Package as Viewed from the Top Surface

7 Pinout Listings

Table 11 provides the pinout listing for the MPC7448, 360 HCTE package. The pinouts of the MPC7448 and MPC7447A are compatible, but the requirements regarding the use of the additional power and ground pins have changed. The MPC7448 requires these pins be connected to the appropriate power or ground plane to achieve high core frequencies; see Section 9.3, “Connection Recommendations,” for additional information. As a result, these pins should be connected in all new designs.

Additionally, the MPC7448 may be populated on a board designed for a MPC7447 (or MPC7445 or MPC7441), provided the core voltage can be made to match the requirements in Table 4 and all pins defined as ‘no connect’ for the MPC7447 are unterminated, as required by the *MPC7457 RISC Microprocessor Hardware Specifications*. The MPC7448 uses pins previously marked ‘no connect’ for the temperature diode pins and for additional power and ground connections. The additional power and ground pins are required to achieve high core frequencies and core frequency will be limited if they are not connected; see Section 9.3, “Connection Recommendations,” for additional information. Because these ‘no connect’ pins in the MPC7447 360 pin package are not driven in functional mode, an MPC7447 can be populated in an MPC7448 board.

NOTE

Caution must be exercised when performing boundary scan test operations on a board designed for an MPC7448, but populated with an MPC7447 or earlier device. This is because in the MPC7447 it is possible to drive the latches associated with the former ‘no connect’ pins in the MPC7447, potentially causing contention on those pins. To prevent this, ensure that these pins are not connected on the board or, if they are connected, ensure that the states of internal MPC7447 latches do not cause these pins to be driven during board testing.

For the MPC7448, pins that were defined as the TEST[0:4] factory test signal group on the MPC7447A and earlier devices have been assigned new functions. For most of these, the termination recommendations for the TEST[0:4] pins of the MPC7447A are compatible with the MPC7448 and will allow correct operation with no performance loss. The exception is BVSEL1 (TEST3 on the MPC7447A and earlier devices), which may require a different termination depending which I/O voltage mode is desired; see Table 3 for more information.

NOTE

This pinout is not compatible with the MPC750, MPC7400, or MPC7410 360 BGA package.

Table 11. Pinout Listing for the MPC7448, 360 HCTE Package (continued)

Signal Name	Pin Number	Active	I/O	Notes
LVRAM	B10	—	—	12, 20, 22
NC (no connect)	A6, A14, A15, B14, B15, C14, C15, C16, C17, C18, C19, D14, D15, D16, D17, D18, D19, E14, E15, F14, F15, G14, G15, H15, H16, J15, J16, J17, J18, J19, K15, K16, K17, K18, K19, L15, L16, L17, L18, L19	—	—	11
LSSD_MODE	E8	Low	Input	6, 12
MCP	C9	Low	Input	
OV _{DD}	B4, C2, C12, D5, F2, H3, J5, K2, L5, M3, N6, P2, P8, P11, R4, R13, R16, T6, T9, U2, U12, U16, V4, V7, V10, V14	—	—	
OVDD_SENSE	E18, G18	—	—	16
PLL_CFG[0:4]	B8, C8, C7, D7, A7	High	Input	
PLL_CFG[5]	D10	High	Input	9, 20
PMON_IN	D9	Low	Input	13
PMON_OUT	A9	Low	Output	
QACK	G5	Low	Input	
QREQ	P4	Low	Output	
SHD[0:1]	E4, H5	Low	I/O	3
SMI	F9	Low	Input	
SRESET	A2	Low	Input	
SYSCLK	A10	—	Input	
TA	K6	Low	Input	
TBEN	E1	High	Input	
TBST	F11	Low	Output	
TCK	C6	High	Input	
TDI	B9	High	Input	6
TDO	A4	High	Output	
TEA	L1	Low	Input	
TEMP_ANODE	N18	—	—	17
TEMP_CATHODE	N19	—	—	17
TMS	F1	High	Input	6
TRST	A5	Low	Input	6, 14
TS	L4	Low	I/O	3
TSIZ[0:2]	G6, F7, E7	High	Output	
TT[0:4]	E5, E6, F6, E9, C5	High	I/O	
WT	D3	Low	Output	
V _{DD}	H8, H10, H12, J7, J9, J11, J13, K8, K10, K12, K14, L7, L9, L11, L13, M8, M10, M12	—	—	
V _{DD}	A13, A16, A18, B17, B19, C13, E13, E16, F12, F17, F19, G11, G16, H14, H17, H19, M14, M16, M18, N15, N17, P16, P18	—	—	15

8 Package Description

The following sections provide the package parameters and mechanical dimensions for the HCTE package.

8.1 Package Parameters for the MPC7448, 360 HCTE BGA

The package parameters are as provided in the following list. The package type is 25 × 25 mm, 360-lead high coefficient of thermal expansion ceramic ball grid array (HCTE).

Package outline	25 × 25 mm
Interconnects	360 (19 × 19 ball array – 1)
Pitch	1.27 mm (50 mil)
Minimum module height	2.32 mm
Maximum module height	2.80 mm
Ball diameter	0.89 mm (35 mil)
Coefficient of thermal expansion	12.3 ppm/°C

8.2 Mechanical Dimensions for the MPC7448, 360 HCTE BGA

Figure 13 provides the mechanical dimensions and bottom surface nomenclature for the MPC7448, 360 HCTE BGA package.

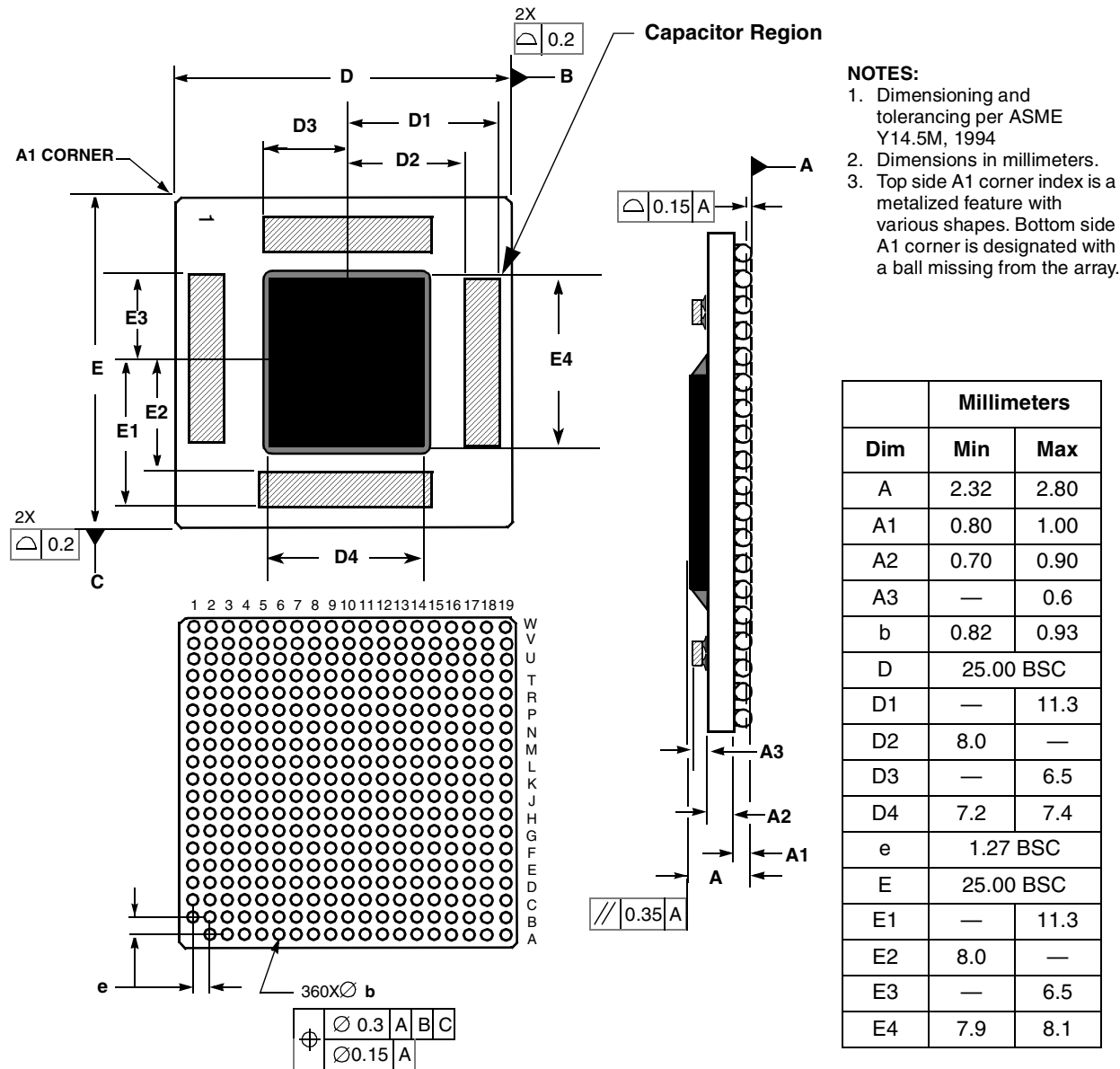


Figure 13. Mechanical Dimensions and Bottom Surface Nomenclature for the MPC7448, 360 HCTE BGA Package

8.4 Mechanical Dimensions for the MPC7448, 360 HCTE LGA

Figure 13 provides the mechanical dimensions and bottom surface nomenclature for the MPC7448, 360 HCTE LGA package.

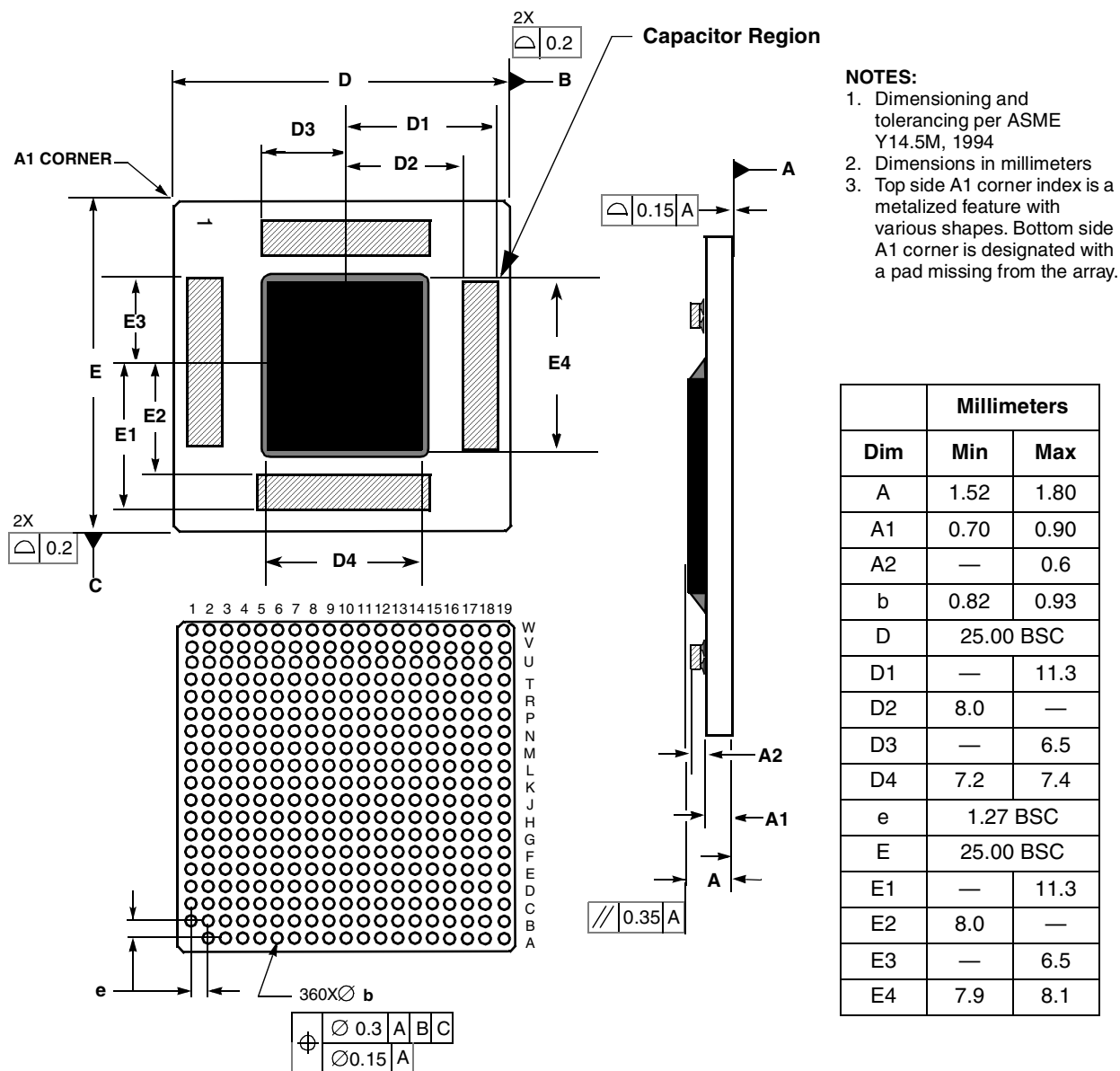


Figure 14. Mechanical Dimensions and Bottom Surface Nomenclature for the MPC7448, 360 HCTE LGA Package

9.1.2 System Bus Clock (SYSCLK) and Spread Spectrum Sources

Spread spectrum clock sources are an increasingly popular way to control electromagnetic interference emissions (EMI) by spreading the emitted noise to a wider spectrum and reducing the peak noise magnitude in order to meet industry and government requirements. These clock sources intentionally add long-term jitter in order to diffuse the EMI spectral content. The jitter specification given in [Table 8](#) considers short-term (cycle-to-cycle) jitter only and the clock generator's cycle-to-cycle output jitter should meet the MPC7448 input cycle-to-cycle jitter requirement. Frequency modulation and spread are separate concerns, and the MPC7448 is compatible with spread spectrum sources if the recommendations listed in [Table 13](#) are observed.

Table 13. Spread Spectrum Clock Source Recommendations

At recommended operating conditions. See [Table 4](#).

Parameter	Min	Max	Unit	Notes
Frequency modulation	—	50	kHz	1
Frequency spread	—	1.0	%	1, 2

Notes:

- Guaranteed by design
- SYSCLK frequencies resulting from frequency spreading, and the resulting core and VCO frequencies, must meet the minimum and maximum specifications given in [Table 8](#).

It is imperative to note that the processor's minimum and maximum SYSCLK, core, and VCO frequencies must not be exceeded regardless of the type of clock source. Therefore, systems in which the processor is operated at its maximum rated core or bus frequency should avoid violating the stated limits by using down-spreading only.

9.2 Power Supply Design and Sequencing

The following sections provide detailed information regarding power supply design for the MPC7448.

9.2.1 Power Supply Sequencing

The MPC7448 requires its power rails and clock to be applied in a specific sequence to ensure proper device operation and to prevent device damage. The power sequencing requirements are as follows:

- AV_{DD} must be delayed with respect to V_{DD} by the RC time constant of the PLL filter circuit described in [Section 9.2.2, "PLL Power Supply Filtering"](#). This time constant is nominally 100 μ s.
- OV_{DD} may ramp anytime before or after V_{DD} and AV_{DD} .

Additionally, the following requirements exist regarding the application of SYSCLK:

- The voltage at the SYSCLK input must not exceed V_{DD} until V_{DD} has ramped to 0.9 V.
- The voltage at the SYSCLK input must not exceed OV_{DD} by more 20% during transients (see overshoot/undershoot specifications in [Figure 2](#)) or 0.3 V DC (see [Table 2](#)) at any time.

9.2.3 Transient Specifications

To ensure the long-term reliability of the device, the MPC7448 requires that transients on the core power rail (V_{DD}) be constrained. The recommended operating voltage specifications provided in Table 4 are DC specifications. That is, the device may be operated continuously with V_{DD} within the specified range without adversely affecting the device's reliability. Excursions above the stated recommended operation range, including overshoot during power-up, can impact the long-term reliability of the device. Excursions are described by their amplitude and duration. Duration is defined as the time period during which the V_{DD} power plane, as measured at the VDD_SENSE pins, will be within a specific voltage range, expressed as percentage of the total time the device will be powered up over the device lifetime. In practice, the period over which transients are measured can be any arbitrary period of time that accurately represents the expected range of processor and system activity. The voltage ranges and durations for normal operation and transients are described in Table 14.

Table 14. VDD Power Supply Transient Specifications

At recommended operating temperatures. See Table 4.

Voltage Region	Voltage Range (V)		Permitted Duration ¹	Notes
	Min	Max		
Normal	V_{DD} minimum	V_{DD} maximum	100%	2
Low Transient	V_{DD} maximum	1.35 V	10%	2, 3
High Transient	1.35 V	1.40 V	0.2%	4

Notes:

1. Permitted duration is defined as the percentage of the total time the device is powered on that the V_{DD} power supply voltage may exist within the specified voltage range.
2. See Table 4 for nominal V_{DD} specifications.
3. To simplify measurement, excursions into the High Transient region are included in this duration.
4. Excursions above the absolute maximum rating of 1.4 V are not permitted; see Table 2.

Note that, to simplify transient measurements, the duration of the excursion into the High Transient region is also included in the Low Transient duration, so that only the time the voltage is above each threshold must be considered. Figure 19 shows an example of measuring voltage transients.

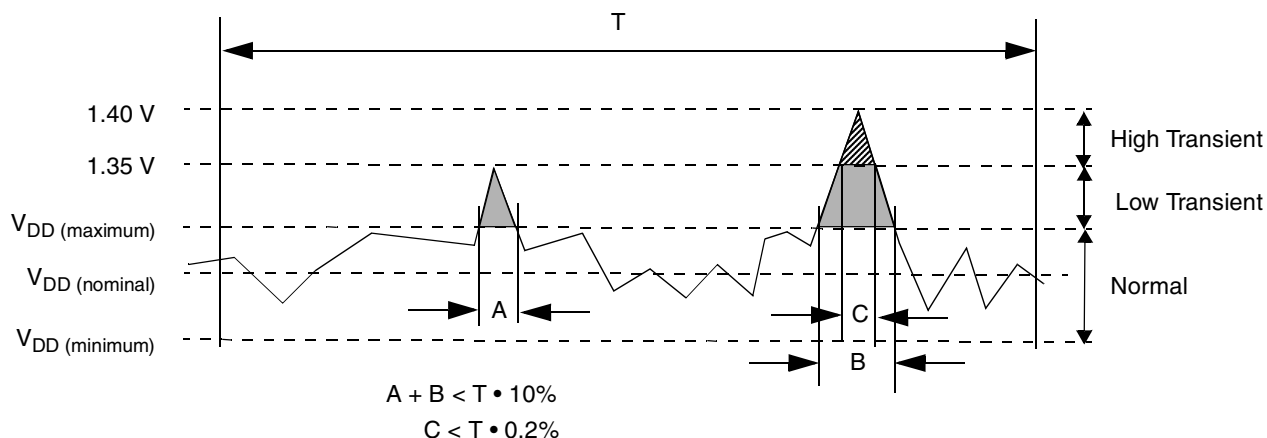


Figure 19. Voltage Transient Example

of any thermal interface material depends on many factors—thermal performance requirements, manufacturability, service temperature, dielectric properties, cost, and so on.

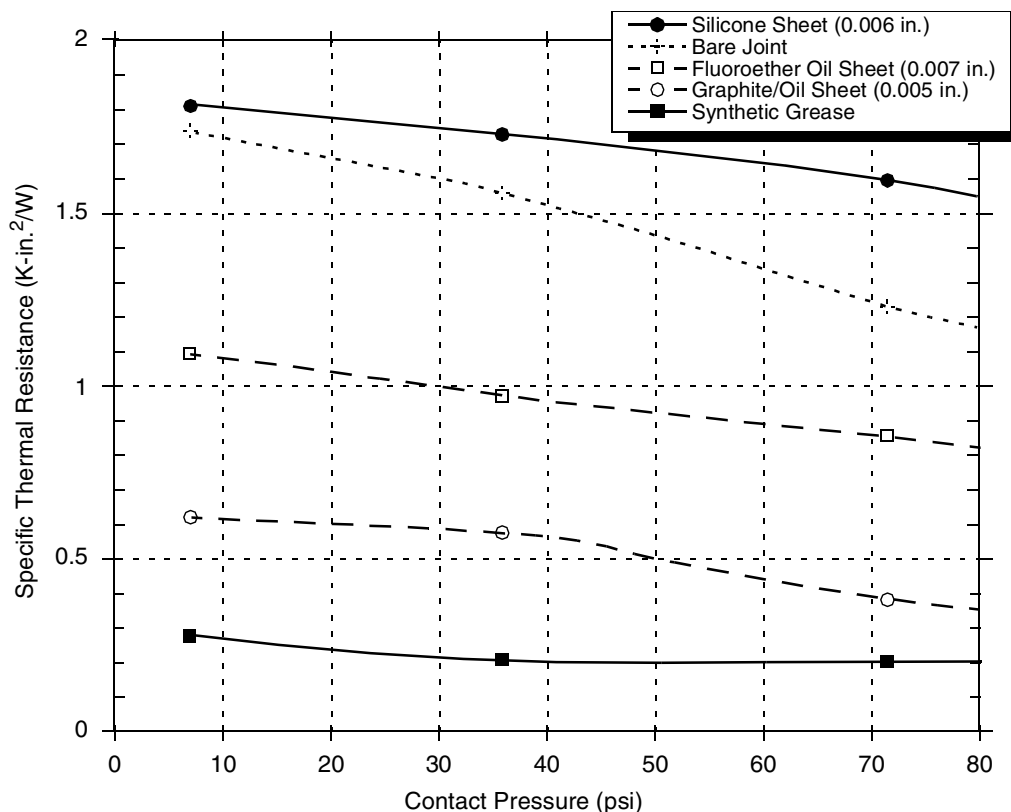


Figure 25. Thermal Performance of Select Thermal Interface Material

The board designer can choose between several types of thermal interfaces. Heat sink adhesive materials should be selected based on high conductivity and mechanical strength to meet equipment shock/vibration requirements. There are several commercially available thermal interfaces and adhesive materials provided by the following vendors:

The Bergquist Company
18930 West 78th St.
Chanhassen, MN 55317
Internet: www.bergquistcompany.com 800-347-4572

Chomerics, Inc.
77 Dragon Ct.
Woburn, MA 01801
Internet: www.chomerics.com 781-935-4850

Dow-Corning Corporation
Corporate Center
P.O. Box 994
Midland, MI 48686-0994
Internet: www.dowcorning.com 800-248-2481

Shin-Etsu MicroSi, Inc.
10028 S. 51st St.
Phoenix, AZ 85044
Internet: www.microsi.com

888-642-7674

Laird Technologies - Thermal
(formerly Thermagon Inc.)
4707 Detroit Ave.
Cleveland, OH 44102
Internet: www.lairdtech.com

888-246-905

The following section provides a heat sink selection example using one of the commercially available heat sinks.

9.7.3 Heat Sink Selection Example

For preliminary heat sink sizing, the die-junction temperature can be expressed as follows:

$$T_j = T_i + T_r + (R_{\theta JC} + R_{\theta int} + R_{\theta sa}) \times P_d$$

where:

- T_j is the die-junction temperature
- T_i is the inlet cabinet ambient temperature
- T_r is the air temperature rise within the computer cabinet
- $R_{\theta JC}$ is the junction-to-case thermal resistance
- $R_{\theta int}$ is the adhesive or interface material thermal resistance
- $R_{\theta sa}$ is the heat sink base-to-ambient thermal resistance
- P_d is the power dissipated by the device

During operation, the die-junction temperatures (T_j) should be maintained less than the value specified in [Table 4](#). The temperature of air cooling the component greatly depends on the ambient inlet air temperature and the air temperature rise within the electronic cabinet. An electronic cabinet inlet-air temperature (T_i) may range from 30°C to 40°C. The air temperature rise within a cabinet (T_r) may be in the range of 5°C to 10°C. The thermal resistance of the thermal interface material ($R_{\theta int}$) is typically about 1.1 °C/W. For example, assuming a T_i of 30°C, a T_r of 5°C, an HCTE package $R_{\theta JC} = 0.1$, and a power consumption (P_d) of 25.6 W, the following expression for T_j is obtained:

$$\text{Die-junction temperature: } T_j = 30^\circ\text{C} + 5^\circ\text{C} + (0.1^\circ\text{C/W} + 1.1^\circ\text{C/W} + \theta_{sa}) \times 25.6$$

For this example, a $R_{\theta sa}$ value of 1.53 °C/W or less is required to maintain the die junction temperature below the maximum value of [Table 4](#).

Though the die junction-to-ambient and the heat sink-to-ambient thermal resistances are a common figure-of-merit used for comparing the thermal performance of various microelectronic packaging technologies, one should exercise caution when only using this metric in determining thermal management because no single parameter can adequately describe three-dimensional heat flow. The final die-junction operating temperature is not only a function of the component-level thermal resistance, but the system-level design and its operating conditions. In addition to the component's power consumption, a number of factors affect the final operating die-junction temperature—airflow, board population (local heat flux of adjacent components), heat sink efficiency, heat sink attach, heat sink placement, next-level interconnect technology, system air temperature rise, altitude, and so on.

Table 16. Valid Divide Ratio Configurations

DFS mode disabled		DFS divide-by-2 mode enabled (HID1[DFS2] = 1 or DFS2 = 0)		DFS divide-by-4 mode enabled (HID1[DFS4] = 1 or DFS4 = 0)	
Bus-to-Core Multiplier Configured by PLL_CFG[0:5] (see Table 12)	HID1[PC0-5] ³	Bus-to-Core Multiplier	HID1[PC0-5] ³	Bus-to-Core Multiplier	HID1[PC0-5] ³
2x ⁴	010000	N/A (unchanged) ¹	unchanged ¹	N/A (unchanged) ¹	unchanged ¹
3x ⁴	100000	N/A (unchanged) ¹	unchanged ¹	N/A (unchanged) ¹	unchanged ¹
4x ⁴	101000	2x ⁴	010000	N/A (unchanged) ¹	unchanged ¹
5x	101100	2.5x ⁴	010101	N/A (unchanged) ¹	unchanged ¹
5.5x	100100	2.75x ⁴	110101 ²	N/A (unchanged) ¹	unchanged ¹
6x	110100	3x ⁴	100000	N/A (unchanged) ¹	unchanged ¹
6.5x	010100	3.25x ⁴	100000 ²	N/A (unchanged) ¹	unchanged ¹
7x	001000	3.5x ⁴	110101	N/A (unchanged) ¹	unchanged ¹
7.5x	000100	3.75x ⁴	110101 ²	N/A (unchanged) ¹	unchanged ¹
8x	110000	4x ⁴	101000 ⁴	2x ⁴	010000
8.5x	011000	4.25x ⁴	101000 ²	N/A (unchanged) ¹	unchanged ¹
9x	011110	4.5x ⁴	011101	2.25x ⁴	010000 ²
9.5x	011100	4.75x ⁴	011101 ²	N/A (unchanged) ¹	unchanged ¹
10x	101010	5x	101100	2.5x ⁴	010101
10.5x	100010	5.25x	101100 ²	N/A (unchanged) ¹	unchanged ¹
11x	100110	5.5x	100100	2.75x ⁴	010101 ²
11.5x	000000	5.75x	100100 ²	N/A (unchanged) ¹	unchanged ¹
12x	101110	6x	110100	3x ⁴	100000
12.5x	111110	6.25x	110100 ²	N/A (unchanged) ¹	unchanged ¹
13x	010110	6.5x	010100	3.25x ⁴	100000 ²
13.5x	111000	6.75	010100 ²	N/A (unchanged) ¹	unchanged ¹
14x	110010	7x	001000	3.5x ⁴	110101
15x	000110	7.5x	000100	3.75x ⁴	110101 ²
16x	110110	8x	110000	4x ⁴	101000
17x	000010	8.5x	011000	4.25x ⁴	101000 ²
18x	001010	9x	011110	4.5x ⁴	011101
20x	001110	10x	101010	5x	101100
21x	010010	10.5x	100010	5.25x	101100 ²

Table 16. Valid Divide Ratio Configurations (continued)

DFS mode disabled		DFS divide-by-2 mode enabled (HID1[DFS2] = 1 or $\overline{\text{DFS2}}$ = 0)		DFS divide-by-4 mode enabled (HID1[DFS4] = 1 or $\overline{\text{DFS4}}$ = 0)	
Bus-to-Core Multiplier Configured by PLL_CFG[0:5] (see Table 12)	HID1[PC0-5] ³	Bus-to-Core Multiplier	HID1[PC0-5] ³	Bus-to-Core Multiplier	HID1[PC0-5] ³
24x	011010	12x	101110	6x	110100
28x	111010	14x	110010	7x	001000

Notes:

1. DFS mode is not supported for this combination of DFS mode and PLL_CFG[0:5] setting. As a result, the processor will ignore these settings and remain at the previous multiplier, as reflected by the HID1[PC0-PC5] bits.
2. Though supported by the MPC7448 clock circuitry, multipliers of $n.25x$ and $n.75x$ cannot be expressed as valid PLL configuration codes. As a result, the values displayed in HID1[PC0-PC5] are rounded down to the nearest valid PLL configuration code. However, the actual bus-to-core multiplier is as stated in this table.
3. Note that in the HID1 register of the MPC7448, the PC0, PC1, PC2, PC3, PC4, and PC5 bits are bits 15, 16, 17, 18, 19, and 14 (respectively). See the *MPC7450 RISC Microprocessor Reference Manual* for more information.
4. Special considerations regarding snooped transactions must be observed for bus-to-core multipliers less than 5x. See the *MPC7450 RISC Microprocessor Reference Manual* for more information.

9.7.5.3 Minimum Core Frequency Requirements with DFS

In many systems, enabling DFS can result in very low processor core frequencies. However, care must be taken to ensure that the resulting processor core frequency is within the limits specified in Table 8. Proper operation of the device is not guaranteed at core frequencies below the specified minimum f_{core} .

10 Document Revision History

Table 17 provides a revision history for this hardware specification.

Table 17. Document Revision History

Revision	Date	Substantive Change(s)
4	3/2007	Table 19: Added 800 MHz processor frequency.
3	10/2006	Section 9.7, "Power and Thermal Management Information": Updated contact information. Table 18, Table 20, and Table 19: Added Revision D PVR. Table 19: Added 600 processor frequency, additional product codes, date codes for 1400 processor frequency, and footnotes 1 and 2. Table 20: Added PPC product code and footnote 1. Table 19 and Table 20: Added Revision D information for 1267 processor frequency.

Table 17. Document Revision History (continued)

Revision	Date	Substantive Change(s)
2		<p>Table 6: Added separate input leakage specification for BVSEL0, $\overline{\text{LSSD_MODE}}$, $\overline{\text{TCK}}$, TDI, TMS, $\overline{\text{TRST}}$ signals to correctly indicate leakage current for signals with internal pull-up resistors.</p> <p>Section 5.1: Added paragraph preceding Table 7 and edited notes in Table 7 to clarify core frequencies at which power consumption is measured.</p> <p>Section 5.3: Removed voltage derating specifications; this feature has been made redundant by new device offerings and is no longer supported.</p> <p>Changed names of “Typical–Nominal” and “Typical–Thermal” power consumption parameters to “Typical” and “Thermal”, respectively. (Name change only—no specifications were changed.)</p> <p>Table 11: Revised Notes 16, 18, and 19 to reflect current recommendations for connection of SENSE pins.</p> <p>Section 9.3: Added paragraph explaining connection recommendations for SENSE pins. (See also Table 11 entry above.)</p> <p>Table 19: Updated table to reflect changes in specifications for MC7448xxnnnnNC devices.</p> <p>Table 9: Changed all instances of TT[0:3] to TT[0:4]</p> <p>Removed mention of these input signals from output valid times and output hold times:</p> <ul style="list-style-type: none"> • AACK, CKSTP_IN, DT[0:3] <p>Figure 17: Modified diagram slightly to correctly show constraint on SYSCLK ramping is related to V_{DD} voltage, not AV_{DD} voltage. (Diagram clarification only; no change in power sequencing requirements.)</p> <p>Added Table 20 to reflect introduction of extended temperature devices and associated hardware specification addendum.</p>
1		<p>Added 1600 MHz, 1420 MHz, and 1000 MHz devices</p> <p>Section 4: corrected die size</p> <p>Table 2: Revised Note 4 to consider overshoot/undershoot and combined with Note 5.</p> <p>Table 4: Revised operating voltage for 1700 MHz device from ± 50 mV to +20 mV / –50 mV.</p> <p>Table 7: Updated and expanded table to include Typical – Nominal power consumption.</p> <p>Table 11: Added voltage derating information for 1700 MHz devices; this feature is not supported at this time for other speed grades.</p> <p>Added transient specifications for VDD power supply in Section 9.2.3, added Table 15 and Figure 19 and renumbered subsequent tables and figures.</p> <p>Moved Decoupling Recommendations from Section 9.4 to Section 9.2.4 and renumbered subsequent sections.</p> <p>Section 9.2.1: Revised power sequencing requirements.</p> <p>Section 9.7.4: Added thermal diode ideality factor information (previously TBD).</p> <p>Table 17: Expanded table to show HID1 register values when DFS modes are enabled.</p> <p>Section 11.2: updated to include additional N-spec device speed grades</p> <p>Tables 18 and 19: corrected PVR values and added “MC” product code prefix</p>
0		Initial public release.

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